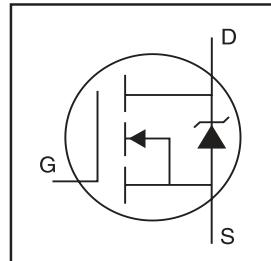


# International IR Rectifier

PD-95622

## IRL2505PbF

HEXFET® Power MOSFET

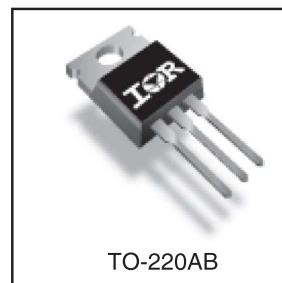
	$V_{DSS} = 55V$ $R_{DS(on)} = 0.008\Omega$ $I_D = 104A^{\circ}$
--	---

- Logic-Level Gate Drive
- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

### Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 is universally preferred for all commercial-Industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.



### Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	104 <sup>⑤</sup>	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	74	
$I_{DM}$	Pulsed Drain Current ①	360	
$P_D @ T_C = 25^\circ C$	Power Dissipation	200	W
	Linear Derating Factor	1.3	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 16	V
$E_{AS}$	Single Pulse Avalanche Energy②	500	mJ
$I_{AR}$	Avalanche Current ①	54	A
$E_{AR}$	Repetitive Avalanche Energy①	20	mJ
$dv/dt$	Peak Diode Recovery dv/dt ③	5.0	V/ns
$T_J$	Operating Junction and	55 to + 175	°C
$T_{STG}$	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	
	Mounting torque, 6-32 or M3 screw	10 lbf·in (1.1N·m)	

### Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	0.75	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50	—	
$R_{\theta JA}$	Junction-to-Ambient	—	62	

# IRL2505PbF

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## Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

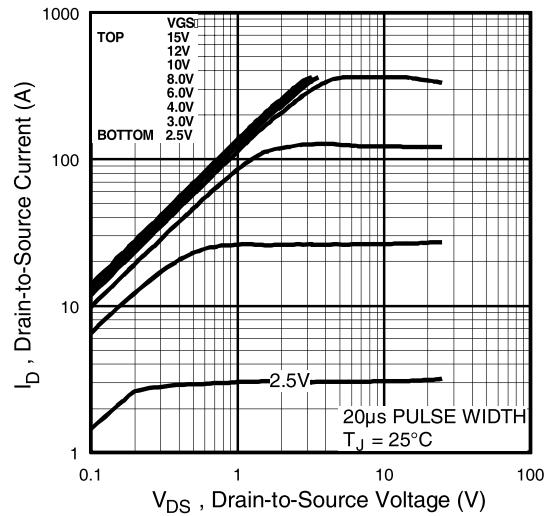
	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	55	---	---	V	$V_{GS} = 0V, I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	---	0.035	---	$\text{V}/^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
$R_{DS(\text{on})}$	Static Drain-to-Source On-Resistance	---	---	0.008	$\Omega$	$V_{GS} = 10V, I_D = 54\text{A}$ ④
		---	---	0.010		$V_{GS} = 5.0V, I_D = 54\text{A}$ ④
		---	---	0.013		$V_{GS} = 4.0V, I_D = 45\text{A}$ ④
$V_{GS(\text{th})}$	Gate Threshold Voltage	1.0	---	2.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
$g_{fs}$	Forward Transconductance	59	---	---	S	$V_{DS} = 25V, I_D = 54\text{A}$
$I_{DSS}$	Drain-to-Source Leakage Current	---	---	25	$\mu\text{A}$	$V_{DS} = 55V, V_{GS} = 0V$
		---	---	250		$V_{DS} = 44V, V_{GS} = 0V, T_J = 150^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	---	---	100	nA	$V_{GS} = 16V$
	Gate-to-Source Reverse Leakage	---	---	-100		$V_{GS} = -16V$
$Q_g$	Total Gate Charge	---	---	130	nC	$I_D = 54\text{A}$
$Q_{gs}$	Gate-to-Source Charge	---	---	25		$V_{DS} = 44V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge	---	---	67		$V_{GS} = 5.0V$ , See Fig. 6 and 13 ④
$t_{d(on)}$	Turn-On Delay Time	---	12	---	ns	$V_{DD} = 28V$
$t_r$	Rise Time	---	160	---		$I_D = 54\text{A}$
$t_{d(off)}$	Turn-Off Delay Time	---	43	---		$R_G = 1.3\Omega, V_{GS} = 5.0V$
$t_f$	Fall Time	---	84	.		$R_D = 0.50\Omega$ , See Fig. 10 ④
$L_S$	Internal Source Inductance	---	7.5	---	nH	Between lead, and center of die contact
$C_{iss}$	Input Capacitance	---	5000	---	pF	$V_{GS} = 0V$
$C_{oss}$	Output Capacitance	---	1100	---		$V_{DS} = 25V$
$C_{rss}$	Reverse Transfer Capacitance	---	390	---		$f = 1.0\text{MHz}$ , See Fig. 5

## Source-Drain Ratings and Characteristics

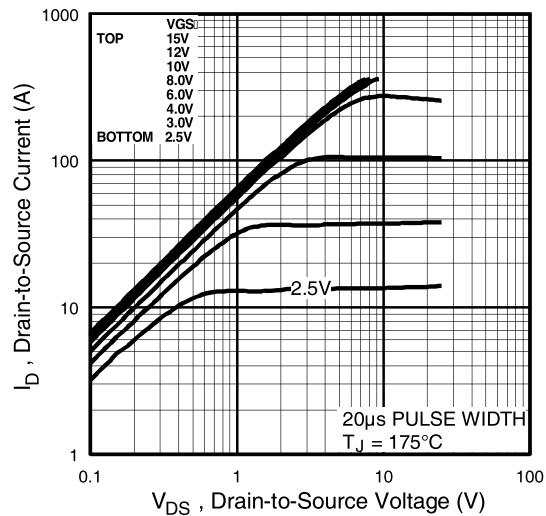
	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	---	---	104⑤	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	Pulsed Source Current (Body Diode) ①	---	---	360		
$V_{SD}$	Diode Forward Voltage	---	---	1.3		$T_J = 25^\circ\text{C}, I_S = 54\text{A}, V_{GS} = 0V$ ④
$t_{rr}$	Reverse Recovery Time	---	140	210	ns	$T_J = 25^\circ\text{C}, I_F = 54\text{A}$
$Q_{rr}$	Reverse Recovery Charge	---	650	970	nC	$di/dt = 100\text{A}/\mu\text{s}$ ④
$t_{on}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S+L_D$ )				

### Notes:

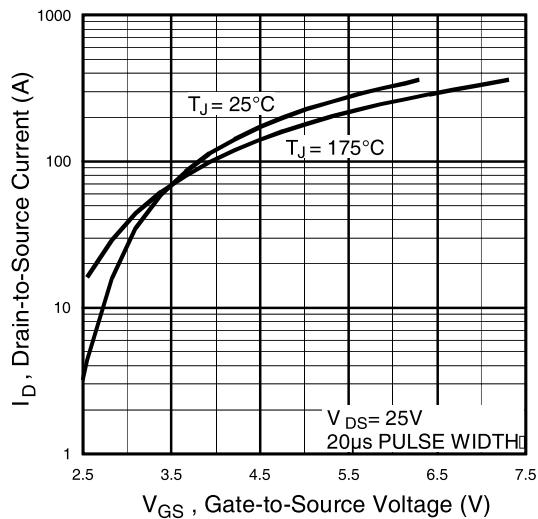
- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- ②  $V_{DD} = 25V$ , starting  $T_J = 25^\circ\text{C}$ ,  $L = 240\mu\text{H}$   $R_G = 25\Omega$ ,  $I_{AS} = 54\text{A}$ . (See Figure 12)
- ③  $I_{SD} \leq 54\text{A}$ ,  $di/dt \leq 230\text{A}/\mu\text{s}$ ,  $V_{DD} \leq V_{(\text{BR})\text{DSS}}$ ,  $T_J \leq 175^\circ\text{C}$
- ④ Pulse width  $\leq 300\mu\text{s}$ ; duty cycle  $\leq 2\%$ .
- ⑤ Calculated continuous current based on maximum allowable junction temperature; for recommended current-handling of the package refer to Design Tip # 93-4



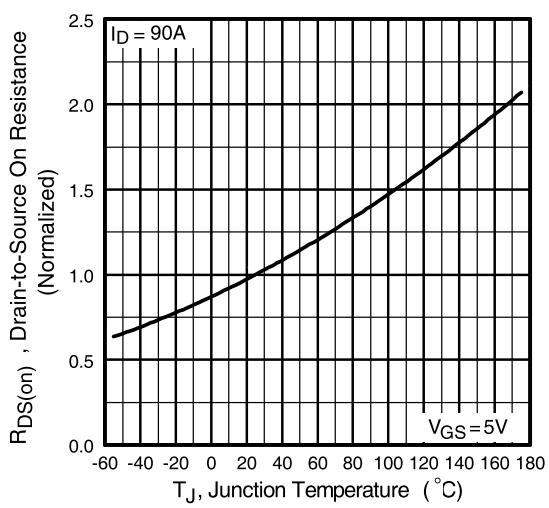
**Fig 1.** Typical Output Characteristics



**Fig 2.** Typical Output Characteristics



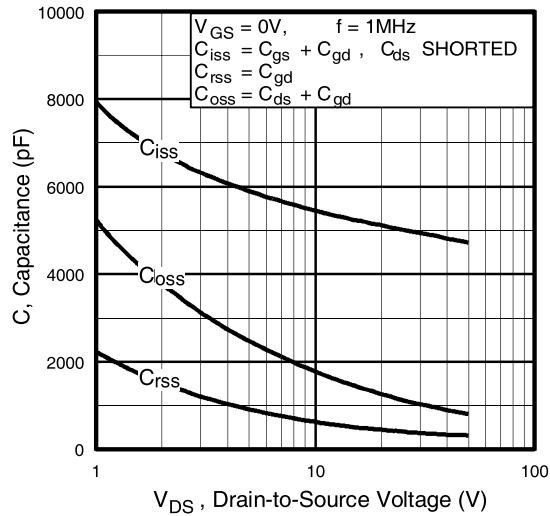
**Fig 3.** Typical Transfer Characteristics



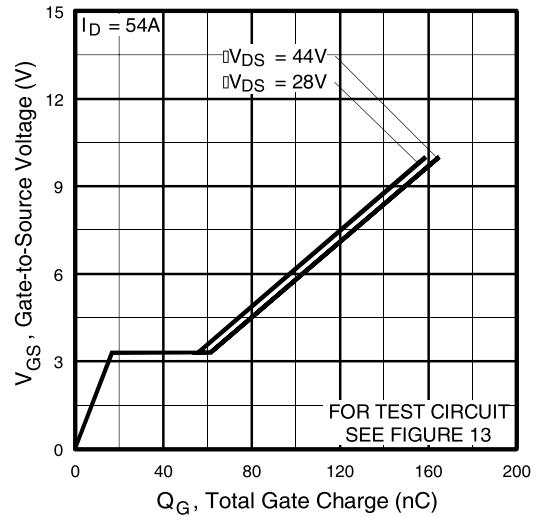
**Fig 4.** Normalized On-Resistance  
Vs. Temperature

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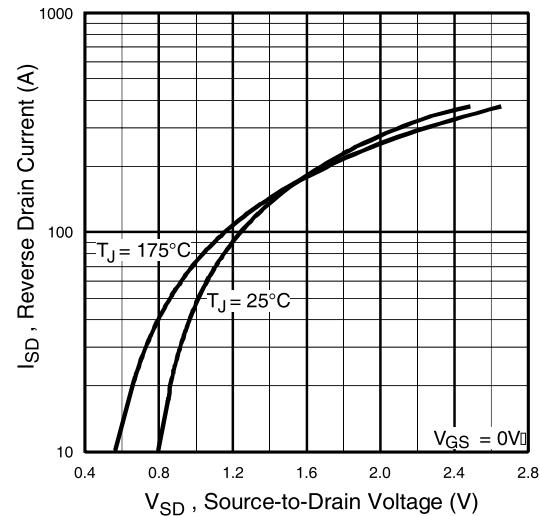
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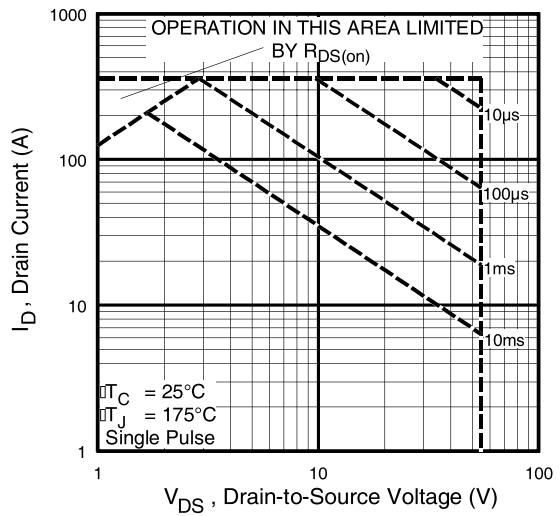
**Fig 5.** Typical Capacitance Vs.  
Drain-to-Source Voltage



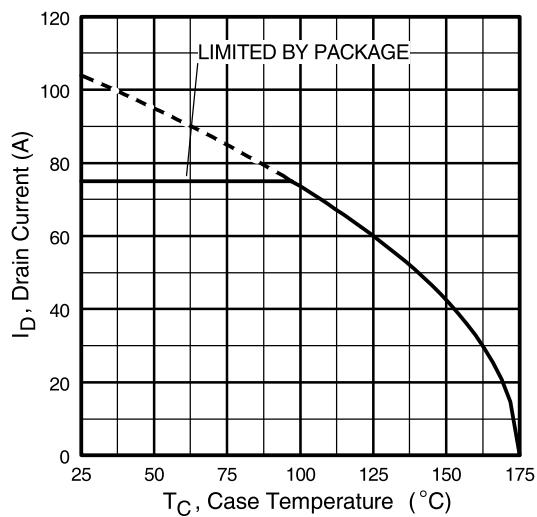
**Fig 6.** Typical Gate Charge Vs.  
Gate-to-Source Voltage



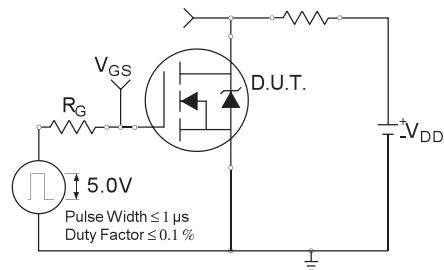
**Fig 7.** Typical Source-Drain Diode  
Forward Voltage



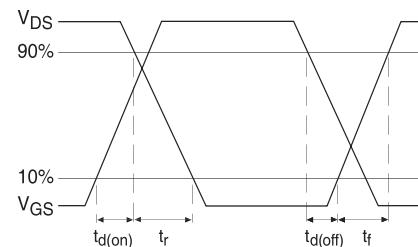
**Fig 8.** Maximum Safe Operating Area



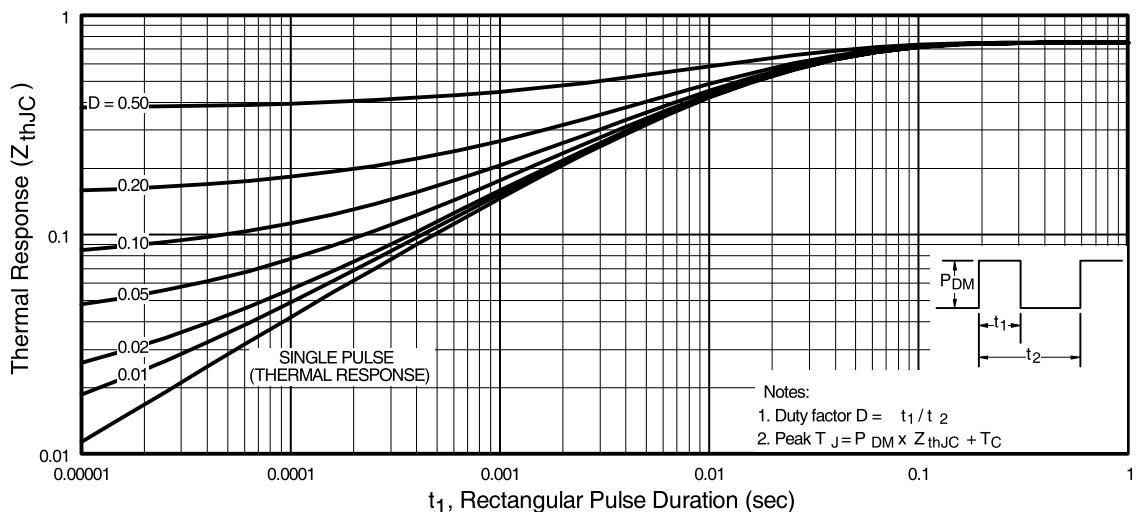
**Fig 9.** Maximum Drain Current Vs.  
Case Temperature



**Fig 10a.** Switching Time Test Circuit



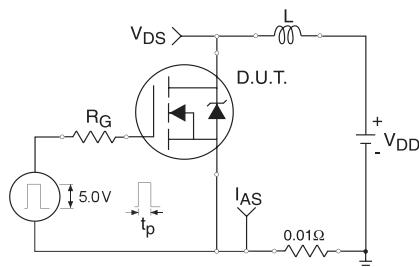
**Fig 10b.** Switching Time Waveforms



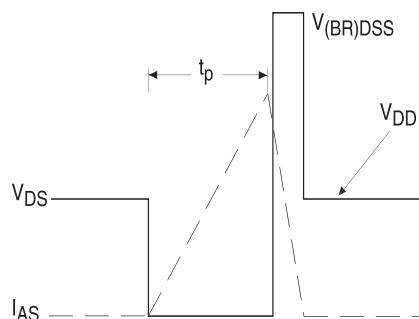
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case

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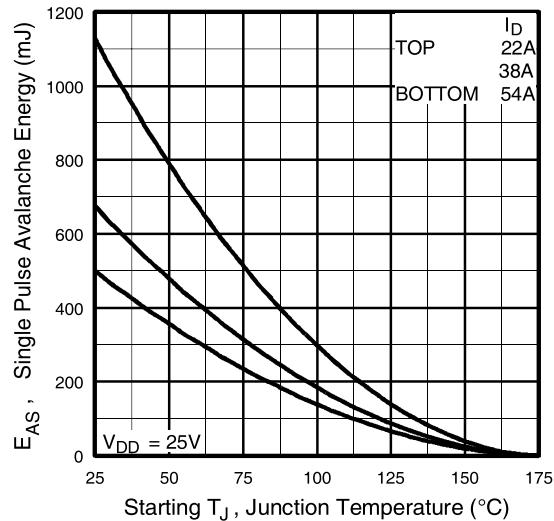
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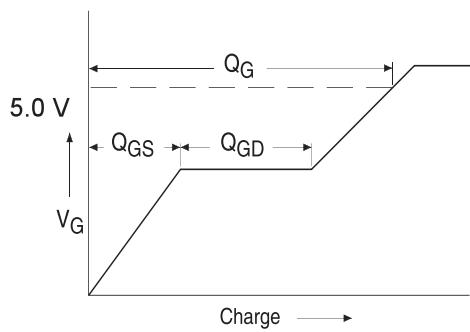
**Fig 12a.** Unclamped Inductive Test Circuit



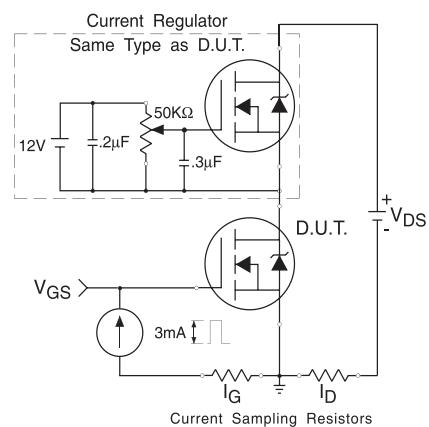
**Fig 12b.** Unclamped Inductive Waveforms



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current



**Fig 13a.** Basic Gate Charge Waveform



**Fig 13b.** Gate Charge Test Circuit

## Peak Diode Recovery dv/dt Test Circuit

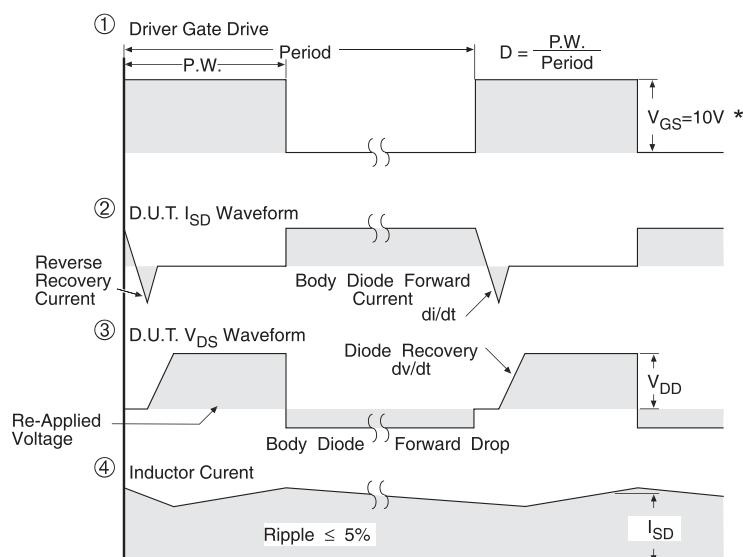
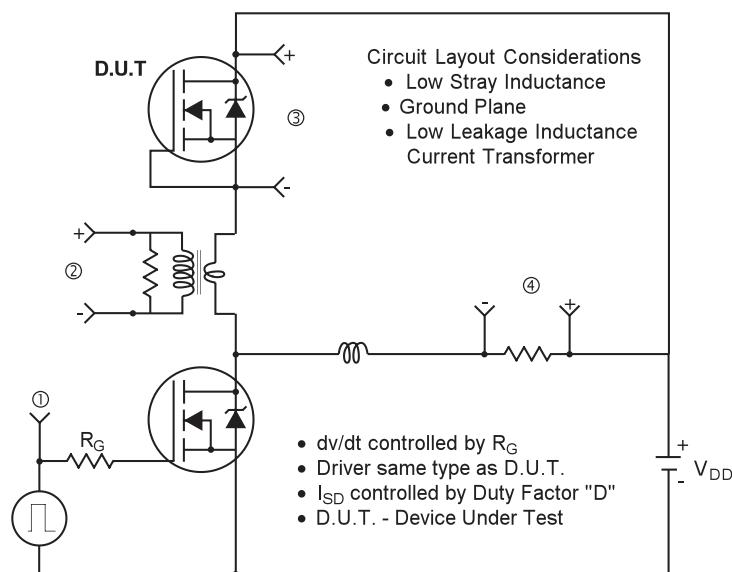


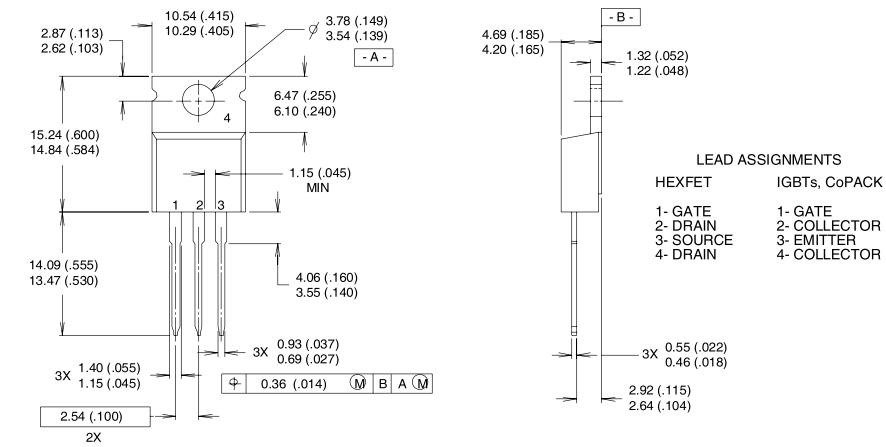
Fig 14. For N-Channel HEXFETs

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## TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



NOTES:

1 DIMENSIONING & TOLERANCING PER ANSI Y14.5M, 1982.

2 CONTROLLING DIMENSION : INCH

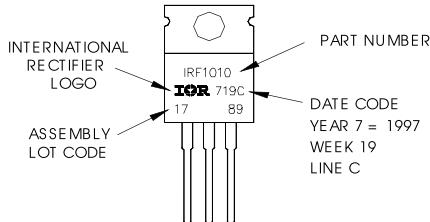
3 OUTLINE CONFORMS TO JEDEC OUTLINE TO-220AB.

4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

## TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010  
LOT CODE 1789  
ASSEMBLED ON WW 19, 1997  
IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line  
position indicates "Lead-Free"



Data and specifications subject to change without notice.  
This product has been designed and qualified for the Industrial market  
Qualification Standards can be found on IR's Web site.

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**IR** Rectifier

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TAC Fax: (310) 252-7903  
Visit us at [www.irf.com](http://www.irf.com) for sales contact information.08/04

Note: For the most current drawings please refer to the IR website at:  
<http://www.irf.com/package/>